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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 129200		APPLICATION NO. 10/590,855	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Naohiro YOSHIDA			
				FILING DATE August 25, 2006		GROUP 3251 2856	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
/M.S./	1.	4,825,198	4/25/1989	ROLKER et al.			
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/M.S./	2.	DE 37 08 471 A1	9/29/1988	Germany			
/M.S./	3.	DE 34 45 281 A1	6/19/1986	Germany	X		
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER				DATE CONSIDERED			
/Mark Shabman/				12/19/2007			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: June 21, 2007

10/590855

IAP9 Rec'd PCT/PTO 25 AUG 2006

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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Naohiro YOSHIDA			
				FILING DATE August 25, 2006			
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Examiner Initials	Cite No.	Document Number	Date	Name			
	1	6,851,298 B2	2/8/2005	Miura et al.			
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/M.S./	2	JP A 2002-151126	5/24/2002	Japan	X	X	
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